The NCSL International Gulf Coast Section convened for a meeting at the JM Test Systems facilities in Baton Rouge, Louisiana. The event was held on May 30, 2019 and hosted by JM Test Systems, Inc. 22 people were in attendance.

The meeting kicked off with a continental breakfast and welcome from Ben Jack, JM Test System’s Alexandria Louisiana Division and Business Development Manager and NCSLI Gulf Coast Section Coordinator. This was followed by introductions of attendees and presenters. A review of the day’s agenda ensued.

The meeting attendees were Ms. Beverly Garcia, JM Test Systems Representative, NCSLI Southeastern Region VP and; Mr. Scott Morrison, CEO JM Test Systems, along with representatives from NASA, Fluke Calibration, FLIR Systems, RKI Instruments, Ametek, Central Louisiana Economic Development Alliance (CLEDA), and JM Test Systems.

The first presentation was delivered by Mr. Scott Crone of Ametek. Scott discussed Deadweight Testers and Digital Pressure Calibrators. After a short break the next presenter was Brent Condie of FLIR Systems. Brent discussed thermography, uses of and interpretations of thermographic imagery. This was followed by Mr. Scott Morrison, JM Test Systems CEO. Mr. Morrison gave a welcome address to the group of attendees and thanked them for their participation. We then went to lunch which was provided by Jason’s Deli of Baton Rouge Louisiana. After lunch, Mr. Mark Price, JM Test Systems, gave a presentation on fiber optics, what it is and how it is used. The final presentation was given by Mr. Wayne Denley, CLEDA VP of Knowledge Platforms. Mr Denley discussed the Advanced Manufacturing Technician (AMT) Program. This is a work/study program partnered by manufacturers and higher learning institutions to offer work and degree opportunities for eligible high school graduates. After Mr. Denley’s presentation, we had a short break and then a tour of the JM Test Systems facilities.

Overall, the meeting was a successful event that shared relevant technical information to the attendees. Thanks to NCSL International for their support and, to our host, JM Test Systems, Inc., and all of the attendees and presenters.

Note: Mr. Darrell Pinkard, RKI Instruments was scheduled to give a morning presentation on The Theory of Gas Detection. Unfortunately, he was not able to be present until later in the afternoon. He did however share a copy of his presentation and it is available to attendees.
REGIONAL NEWS

Ben Jack, JM Test and NCSLI Section Coordinator with attendees.

Scott Crone, Ametek.

Brent Conde, FLIR Systems.

Scott Morrison, President of JM Test Systems, Inc.

Marty Kid, Fluke Calibration.

Mark Price, JM Test Systems, Inc.